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Application/Control No.	Applicant(s)/Patent under Reexamination
10/705,895	OGIHARA ET AL.
Examiner	Art Unit
Hai C. Pham	2861

SEARCHED						
Class	Subclass	Date	Examiner			
347	233, 237- 238, 247	12/7/2005	HP			
257	72, 690	12/7/2005	HP			

INI	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCI (INCLUDING SEA	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
EAST Text Search	12/7/2005	НР		